Application No. 09/742,224 Inventor: Walx FANG ET AL

Replacement Sheet

Provides numerous integrated circuits. Whereby, each integrated circuit is similar to other integrated circuits except unavoidable tolerance of fabricating process.

Performing a life-time testing process to establish a experimental failure rate versus testing time relation by measuring the life-time or failure rate of each said integrated circuit under a testing environment.

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Performing a simulating process that uses a test life function for curve fitting to simulate the experimental failure rate versus testing time relation.

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performing a transforming process that uses the acceleration factor function to transform the simulated failure rate versus testing time function into a real failure rate versus operation time function.

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Performing an integrating process that integrates the real failure rate versus operation time function through a calculating region to obtain a yield ratio equal to the area under the curve of the real failure rate versus operation time function.

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